

AMENDMENTS TO THE CLAIMS

This listing of claims will replace all prior versions or listings of claims for this application.

Listing of Claims:

1. (Currently amended) A pixel cell comprising:

at least one transistor structure comprising:

at least one semiconductor channel region;

at least one gate for controlling the channel region; and

first and second leads respectively coupled to a source region

on one side of the at least one channel region and a drain

region on an opposite side of the at least one channel region,

wherein the at least one transistor structure has at least two

threshold voltages associated with the at least one channel

region, and wherein an $[[I-V]]$ current-voltage characteristic of

the transistor structure is determined at least in part by the

threshold voltages.
2. (Original) The pixel cell of claim 1, wherein the at least one

transistor structure is an active element for operating at least in

part in a sub-threshold region.
3. (Original) The pixel cell of claim 1, wherein the at least one

transistor structure is a source follower transistor structure.

4. (Original) The pixel cell of claim 1, wherein the at least one transistor structure comprises first, second, and third channel regions connected in parallel.
5. (Currently amended) The pixel cell of claim 4, wherein the first channel region corresponds to a ~~highest~~ first threshold voltage and the second and third channel regions correspond to second and third threshold voltages, respectively, and wherein the first threshold voltage is higher than the second and third threshold voltages.
6. (Currently amended) The pixel cell of claim 4, wherein a first channel region corresponds to a ~~highest~~ first threshold voltage and second and third channel regions correspond to a second threshold voltage, and wherein the first threshold voltage is higher than the second threshold voltage.
7. (Original) The pixel cell of claim 1, wherein the at least one transistor structure comprises one channel region, and wherein the channel region comprises a normal conduction path and at least one parasitic conduction path.
8. (Original) The pixel cell of claim 7, wherein the normal conduction path is associated with a highest first threshold voltage and the at least one parasitic conduction path is associated with at least a second lower threshold voltage.

9. (Original) The pixel cell of claim 8, wherein the transistor structure comprises first and second parasitic conduction paths, and wherein the first and second parasitic conduction paths are associated with a second threshold voltage.
10. (Original) The pixel cell of claim 8, wherein the transistor structure comprises first and second parasitic conduction paths, and wherein the first and second parasitic conduction paths are associated with second and third threshold voltages, respectively.
11. (Original) The pixel cell of claim 1, wherein the two or more threshold voltages result at least in part from the at least one transistor structure having any of: two or more gate oxide thicknesses, two or more channel dopant concentrations, and two or more gate work-functions.
12. (Currently amended) The pixel cell of claim 1, wherein the [[I-V]]current-voltage characteristic is such that a sub-threshold region and a linear region provide a same or similar amplification factor for a signal.
13. (Original) The pixel cell of claim 1, further comprising a photo-conversion device.
14. (Original) The pixel cell of claim 13, wherein the photo-conversion device is a pinned photodiode.

15. (Withdrawn) A pixel cell comprising:
 - a photo-conversion device; and
 - at least one transistor structure comprising:
 - first, second, and third semiconductor channel regions;
 - at least one gate for controlling the channel regions; and
 - first and second leads respectively coupled to source regions on one side of the channel regions and drain regions on an opposite side of the channel regions, wherein the first channel region is associated with a highest first threshold voltage, and wherein the second and third channel regions are associated with at least a second threshold voltage, and wherein an I-V characteristic of the transistor structure is determined at least in part by the threshold voltages.
16. (Withdrawn) The pixel cell of claim 15, wherein the at least one transistor structure is an active element for operating at least in part in a sub-threshold region.
17. (Withdrawn) The pixel cell of claim 15, wherein the at least one transistor structure is a source follower transistor structure.
18. (Withdrawn) The pixel cell of claim 15, wherein the second and third channel regions are associated with second and third threshold voltages, respectively.

19. (Withdrawn) The pixel cell of claim 15, wherein the two or more threshold voltages result at least in part from the at least one transistor structure having any of: two or more gate oxide thicknesses, two or more channel dopant concentrations, and two or more gate work-functions.
20. (Currently amended) A pixel cell comprising:
- a photo-conversion device; and
 - at least one transistor structure comprising:
 - a channel region;
 - a gate for controlling the channel region; and
 - first and second leads respectively coupled to a source region on one side of the channel region and a drain region on an opposite side of the channel region, wherein the channel region comprises a normal conduction path and at least one parasitic conduction path, and wherein the normal conduction path is associated with a highest first threshold voltage, and wherein the at least one parasitic conduction path is associated with at least a second threshold voltage, and wherein an I - V current-voltage characteristic of the transistor structure is determined at least in part by the threshold voltages.

21. (Original) The pixel cell of claim 20, wherein the at least one transistor structure is an active element for operating at least in part in a sub-threshold region.
22. (Original) The pixel cell of claim 20, wherein the at least one transistor structure is a source follower transistor structure.
23. (Original) The pixel cell of claim 20, wherein the channel region comprises first and second parasitic conduction paths, and wherein the first and second parasitic conduction paths are associated with second and third threshold voltages, respectively.
24. (Original) The pixel cell of claim 20, wherein the first and at least second threshold voltages result at least in part from the at least one transistor structure having any of: at least two gate oxide thicknesses and at least two channel dopant concentrations.
25. (Currently amended) An image sensor, comprising:
an array of pixel cells, wherein at least one of the pixel cells comprises:
a photo-conversion device; and
a transistor structure, the transistor structure comprising:
at least one semiconductor channel region;
at least one gate for controlling the channel region; and

first and second leads respectively coupled to a source region on one side of the at least one channel region and a drain region on an opposite side of the at least one channel region, wherein the transistor structure has at least two threshold voltages associated with the at least one channel region, and wherein an $[[I-V]]$ current-voltage characteristic of the transistor structure is determined at least in part by the threshold voltages.

26. (Original) The image sensor of claim 25, wherein the transistor structure is an active element for operating at least in part in a sub-threshold region.
27. (Original) The image sensor of claim 25, wherein the transistor structure is a source follower transistor structure.
28. (Original) The image sensor of claim 25, wherein the transistor structure comprises first, second, and third channel regions connected in parallel.
29. (Currently amended) The image sensor of claim 28, wherein the first channel region corresponds to a ~~highest~~ first threshold voltage and the second and third channel regions correspond to second and third threshold voltages, respectively, and wherein the first threshold voltage is higher than the second and third threshold voltages.

30. (Currently amended) The image sensor of claim 28, wherein the first channel region corresponds to a ~~highest~~ first threshold voltage and the second and third channel regions correspond to a second threshold voltage, and wherein the first threshold voltage is higher than the second threshold voltage.
31. (Original) The image sensor of claim 25, wherein the transistor structure comprises one channel region, and wherein the channel region comprises a normal conduction path and at least one parasitic conduction path.
32. (Original) The image sensor of claim 31, wherein the normal conduction path is associated with a highest first threshold voltage and the at least one parasitic conduction path is associated with at least a second threshold voltage.
33. (Original) The image sensor of claim 32, wherein the transistor structure comprises first and second parasitic conduction paths, and wherein the first and second parasitic conduction paths are associated with a second threshold voltage.
34. (Original) The image sensor of claim 32, wherein the transistor structure comprises first and second parasitic conduction paths, and wherein the first and second parasitic

conduction paths are associated with second and third

threshold voltages, respectively.

35. (Original) The image sensor of claim 25, wherein the two or more threshold voltages result at least in part from the transistor structure having one or more of: two or more gate oxide thicknesses, two or more channel dopant concentrations, and two or more gate work-functions.
36. (Currently amended) The image sensor of claim 25, wherein the [[I-V]]current-voltage characteristic is such that a sub-threshold region and a linear region provide a same or similar amplification factor for a signal.
37. (Original) The image sensor of claim 25, further comprising a photo-conversion device.
38. (Original) The image sensor of claim 37, wherein the photo-conversion device is a pinned photodiode.
39. (Currently amended) A processor system, comprising:
- (i) a processor; and
 - (ii) an image sensor coupled to the processor, the image sensor comprising:
one or more pixel cells, the one or more pixel cells comprising:
a photo-conversion device and a transistor structure, the transistor structure comprising:

at least one semiconductor channel region;
at least one gate for controlling the channel region; and
first and second leads respectively coupled to a source region
on one side of the at least one channel region and a drain
region on an opposite side of the at least one channel region,
wherein the transistor structure has at least two threshold
voltages associated with the at least one channel region, and
wherein an $[[I-V]]$ current-voltage characteristic of the
transistor structure is determined at least in part by the
threshold voltages.

Claims 40-59 (Canceled).

60. (New) The system of claim 39, wherein the transistor structure is an active element for operating at least in part in a sub-threshold region.
61. (New) The system of claim 39, wherein the transistor structure comprises first, second, and third channel regions connected in parallel.
62. (New) The system of claim 39, wherein the first channel region corresponds to a first threshold voltage and the second and third channel regions correspond to second and third threshold voltages, respectively, and wherein the first, second and third threshold voltages are different from one another.

63. (New) The system of claim 28, wherein the first channel region corresponds to a first threshold voltage and the second and third channel regions correspond to a second threshold voltage, and wherein the first threshold voltage is different than the second threshold voltage.